

Hierarchical design error diagnosis in combinational circuits by stuck-at fault test patterns

Ubar, Raimund-Johannes; Jutman, Artur Proceedings of the 6th International Conference on Mixed Design of Integrated Circuits and Systems : MIXDES'99 : Krakow, Poland, 17-19 June 1999 1999 / p. 437-442 : ill
<https://www.sciencedirect.com/science/article/pii/S0026271499002036>